

TABLE I. DEVICE PARAMETERS 1/

JPL PART # ST12212-	MFG	MFG PART #	PACKAGE STYLE	DETAIL SCREENING TESTS	ELECTRICAL CHARACTERISTICS & GROUP A TESTS	RADIATION (TID) LEVEL RAD(Si)
DN415ØBR	MSC	1N415Ø	DO-35 2/	MIL-S- 195ØØ/231	MIL-S-195ØØ/231 (TABLE I)	1ØØk 3/

NOTES:

- 1/ This drawing in conjunction with CS515581, imposes all requirements for procurement of these devices.
- 2/ Device physical dimensions shall conform to MIL-S-195ØØ/231, Figure 1.
- 3/ Sufficient radiation tolerance to this TID level is guaranteed by design for this device.
(See CS515581, Paragraph 4.7.7).
4. Final finish of leads shall be hot solder dip in accordance with MIL-S-195ØØ.
5. This standard takes precedence over documents referenced herein.

RELEASED THRU SECTION 356 DATA MANAGEMENT:			DATE:		
REVISION: B APPROVED BY:			DATE:		
APPROVED SOURCE(S)					THE ITEM LISTED IN THE APPROVED SOURCE BLOCK AND IDENTIFIED BY VENDOR NAME, ADDRESS, AND PART NUMBER WILL BE EVALUATED AND TESTED BY THE JPL ELECTRONIC PARTS RELIABILITY SECTION OR ITS DELEGATED ALTERNATE BEFORE BEING APPROVED FOR USE. NON-JPL USERS SHALL CHECK WITH THE ELECTRONIC PARTS RELIABILITY SECTION ON THE STATUS OF THE PART'S APPROVAL BEFORE USING.
VENDOR PART NO	VENDOR	JPL PART NO			
JET PROPULSION LABORATORY CALIFORNIA INSTITUTE OF TECHNOLOGY					CAGE NO 23835
Procurement specification: CS515581 Screening specification: ZPP-2Ø73-GEN	TITLE: <div style="text-align: center;">DIODE, SILICON, LOW POWER SWITCHING, 2ØØmA, 5ØV</div>			DETAIL SPECIFICATION	
Custodian: Electronic Parts Reliability Section 514				ST 12212	
			SHEET 1 OF 1		